

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KANBE ET AL.	
		Examiner James A. Dudek	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0004686	01-2004	Ogawa et al.	349/114
	B	US-2003/0210369	11-2003	Wu, Shin-Tson	349/114
	C	US-2003/0206256	11-2003	Drain et al.	349/113
	D	US-2003/0156240	08-2003	Oda et al.	349/113
	E	US-2003/0156239	08-2003	Inoue et al.	349/113
	F	US-2003/0117553	06-2003	Yamada, Yoshitaka	349/113
	G	US-2001/0012085	08-2001	Johnson et al.	349/143
	H	US-6,683,667	01-2004	Jin et al.	349/113
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*	:	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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